Silicon Finger 2.0

A High Parallelism, High Bandwidth Probecard using Silicon Finger MEMS probes





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Program Outline

- Introduction to the Silicon Finger Probe Card (SiFi 2.0)
- > Overview of Silicon Finger probe fabrication
- > Overview of Silicon Finger probecard manufacturing methods
- > Overview of Silicon Finger probecard design methods
- > Overview of probecard characteristics



Silicon Finger Probecard Components Silicon Finger Combs

Silicon base and underside of finger



SEM of whole comb on tape

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SEM Image of probe tips





Ni trace

Silicon Finger Probecard Components Example MLC

Ceramic Size 6mm Ceramic Flatness -3dB Bandwidth (MLC & PCB) Routed Layer Count

6mm x 100mm x 75mm 10um B) 1.85GHz 19



Multi Layer Ceramic



Combs on MLC

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Silicon Finger Probecard Components PCB

44

2052

6.35mm

355mm

PCB Layers: Signal Count: PCB Thickness: PCB Diameter



PCB



PCB Impedance $50\Omega \pm 3\Omega$ PCB Flatness0.005 in/1 in



LGA region of PCB for connection to MLC

Silicon Finger Probecard Assembled



Not Shown - Fasteners, Spacers and elastomer



Silicon Finger Comb Fabrication Silicon Etching





Comb back side



Probes



Silicon Finger Comb Fabrication Metal Plating





Silicon Finger Comb Fabrication Finished Wafer



Completed wafer diced and combs removed from tape.

Full Q/A

- Isolation
- Dimensional
- Visual



Silicon Finger Probecard Assembly Cleanroom



Wire Bonding

Comb Mounting



Silicon Finger Probecard Assembly Comb Mounting





Alignment and Mounting to Ceramic Substrate







Silicon Finger Probecard Assembly Wire Bonding



Wire bonding system





Silicon Finger Probecard Design

- Automatic netlist creation and verification.
- > Automatic PCB layout routing.



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Silicon Finger Probecard Specifications Overview

Tip accuracy	+/- 10 microns
Minimum Pitch	80 microns
Minimum Overdrive	10 microns
Spring rate	1 gm/mil
-3dB Bandwidth	1.30 GHz
(Probecard)	
Cres	0.5Ω
Inductance (SiFi probe	1 nH
only)	
Length	1.585 m m
DUTs in Parallel	X63 full pin count,
	X512 Design for Test
TD life	500,000 cycles



Silicon Finger Probecard Characteristics; Probe Tips



Optical view of probe tips via prober

Width 12 to 18 um Length depends upon overdrive



Optical view of scrub marks via prober



Silicon Finger Probecard Characteristics; Cres Vs Overdrive





Silicon Finger Probecard Characteristics; Insertion Loss

Insertion loss S21 (f) whole probecard



The -3dB point is reached at 1.3 GHz.



Silicon Finger Probecard Characteristics; Timing Error

Typical Reflections from 40 Randomly selected traces



Timing errors <70 ps and impedance at 50 +/- 3 Ohms.



Silicon Finger Probecard Characteristics; Rise Time

Time domain transmission - whole probecard



20%-80% risetime = 121 ps 10%-90% risetime = 207 ps



Silicon Finger Probecard Characteristics; Cross Talk



Crosstalk for the probecard is well within typical specs.



Silicon Finger Probe only Characteristics; Risetime



With SiFi Added Delay 7.5 ps

Measurement System w/o SiFi



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Silicon Finger Probe only Characteristics; Insertion Loss





Less than 3db insertion loss to 30 GHz



Silicon Finger Probe only Characteristics; Capacitance





0.1 pF to above 20 GHz



Probe only Characteristics; Inductance





Less than 1nH up to 15 Ghz in G-S-G arrangement

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